

# ASC TF3 Wavefront standard: Action Items from 5/11/2009 meeting

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## General:

1. Change document numbers so that “Form and Figure” document precedes (numerically) “Texture” document. Specifically:
  - a. Document previously referred to OP1.005 becomes: BSR/OEOSC OP1.004 “Optics and Electro-Optical Instruments – Optical Elements and Assemblies – Form, figure and wavefront measurement”
  - b. Document previously referred to OP1.004 becomes: BSR/OEOSC OP1.005 “Optics and Electro-Optical Instruments – Optical Elements and Assemblies – Texture measurement”
2. C. Evans and P. Takacs to confirm “scope” for each document to G. Kohlenberg by 6/15/2009
3. G. Kohlenberg to provide appropriate document to ANSI
4. Next version of both documents due September, 2009
5. Teleconference to review documents in October 2009
6. C. Evans and P. Takacs to confirm consistent notation between OP1.004 and 1.005 and with extant ISO standards, including 10110, 1302, 3274, 4287, 11562, and 25178 after October telecon
7. “Line-by-line” review of both documents January 2010 at Photonics West (San Francisco)
8. Committee ballot after January 2010 meeting
9. C. Evans and P. Takacs to provide G. Kohlenberg with PDFs, not docx

## Texture (old OP1.004)

1. P. Takacs to add criteria for loop in Figure 1
2. P. Takacs to add section on slope
3. Outlier removal to be added.

## Form, figure and wavefront (old OP1.005)

1. All committee members to review new structure (see Action items from Jan 1009) of “definitions” (Section 3) and “Description of a surface or wavefront” (Section 4) for consistency following extensive rewrite. Reviews due by June 15<sup>th</sup>, 2009
2. Discrete rms definition by cross-reference to ISO 25178 and/or ANSA B.46 (C. Evans)
3. Change terminology for Zernikes from “normalized” and “non-normalized” to “orthogonal” and “orthonormal” (C. Evans)
4. Add flow chart to Section 4 (C. Evans)
5. Add Section 5 – indication in drawings (D. Aikens)

6. Section 10: add 2 examples of uncertainty evaluations – one that is largely analytical (eg uncertainty in rms) and one based on a Monte Carlo (C. Evans).